

Form PTO 1449  
(Modified)DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

248760US0RDCONT

SERIAL NO.

New Continuation of  
10/188,744

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yasuo OHBA

FILING DATE

Herewith

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	4,792,958	12/20/88	OHBA, et al.			
	AB	4,809,287	02/28/89	OHBA, et al.			
	AC	4,835,117	05/30/89	OHBA, et al.			
	AD	4,949,349	08/14/90	OHBA, et al.			
	AE	4,910,743	03/20/90	OHBA, et al.			
	AF	4,928,285	05/22/90	KUSHIBE, et al.			
	AG	4,893,313	01/09/90	HATAKOSHI, et al.			
	AH	5,076,800	12/31/91	MILNES, et al.			
	AI	5,036,521	07/30/91	HATAKOSHI, et al.			
	AJ	5,168,077	12/01/92	ASHIZAWA, et al.			
	AK	5,042,043	08/20/91	HATANO, et al.			
	AL	5,005,057	04/02/91	IZUMIYA, et al.			
	AM	5,079,184	01/07/92	HATANO, et al.			
	AN	5,103,271	04/07/92	IZUMIYA, et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	2000-31588	01/28/00	JAPAN		
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pp. L 905 - L 906, "FABRICATION AND CHARACTERIZATION OF AlGaIn/GaN DOUBLE-HETEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING SINGLE CRYSTALLINE AlN BUFFER LAYERS," August 1, 1998.				
	AX					
	AY					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA	5,228,044	07/13/93	OHBA			
	AB	5,235,194	08/10/93	IZUMIYA, et al.			
	AC	5,273,933	12/28/93	HATANO, et al.			
	AD	5,317,167	05/31/94	IZUMIYA, et al.			
	AE	5,432,808	07/11/95	HATANO, et al.			
	AF	5,617,438	04/01/97	HATANO, et al.			
	AG	5,740,192	04/14/98	HATANO, et al.			
	AH	5,998,810	12/07/99	HATANO, et al.			
	AI	6,242,764	06/05/01	Y. OHBA, et al.			
	AJ	5,990,495	11/23/99	Y. OHBA			
	AK	5,656,832	06/01/99	Y. OHBA, et al.			
	AL	5,909,040	06/01/99	Y. OHBA, et al.			
	AM	5,929,466	07/27/99	Y. OHBA, et al.			
	AN						
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	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES                      NO			
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	AW	<div style="border: 1px solid black; height: 100px; width: 100%;"></div>					
	AX						
	AY						
	AZ						
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	AA	5,146,465	09/92	KHAN, et al.			
	AB	6,259,122	07/01	OTA, et al.			
	AC	5,875,052	02/99	SHMAGIN, et al.			
	AD	6,306,672 B1	10/01	KIM			
	AE	6,046,464	04/00	SCHETZINA			
	AF	6,440,823 B1	08/02	VAUDO, et al.			
	AG	5,929,467	07/99	KAWAI, et al.			
	AH	5,923,058	07/99	AGARWAL, et al.			
	AI						
	AJ						
	AK						
	AL						
	AM						
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